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# Ignition IGBT, 18 A, 400 V

## **N-Channel DPAK**

This Logic Level Insulated Gate Bipolar Transistor (IGBT) features monolithic circuitry integrating ESD and Over–Voltage clamped protection for use in inductive coil drivers applications. Primary uses include Ignition, Direct Fuel Injection, or wherever high voltage and high current switching is required.

#### **Features**

- Ideal for Coil-on-Plug Applications
- DPAK Package Offers Smaller Footprint for Increased Board Space
- Gate-Emitter ESD Protection
- Temperature Compensated Gate–Collector Voltage Clamp Limits Stress Applied to Load
- Integrated ESD Diode Protection
- New Design Increases Unclamped Inductive Switching (UIS) Energy Per Area
- Low Threshold Voltage Interfaces Power Loads to Logic or Microprocessor Devices
- Low Saturation Voltage
- High Pulsed Current Capability
- Optional Gate Resistor (R<sub>G</sub>) and Gate-Emitter Resistor (R<sub>GE</sub>)
- Emitter Ballasting for Short-Circuit Capability
- These are Pb-Free Devices

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	V <sub>CES</sub>	430	$V_{DC}$
Collector-Gate Voltage	V <sub>CER</sub>	430	$V_{DC}$
Gate-Emitter Voltage	V <sub>GE</sub>	18	$V_{DC}$
Collector Current–Continuous @ T <sub>C</sub> = 25°C – Pulsed	I <sub>C</sub>	15 50	A <sub>DC</sub> A <sub>AC</sub>
ESD (Human Body Model) R = 1500 $\Omega$ , C = 100 pF	ESD	8.0	kV
ESD (Machine Model) R = 0 $\Omega$ , C = 200 pF	ESD	800	V
Total Power Dissipation @ T <sub>C</sub> = 25°C Derate above 25°C	P <sub>D</sub>	115 0.77	Watts W/°C
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C

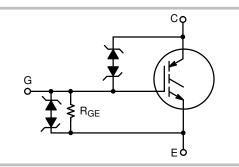
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



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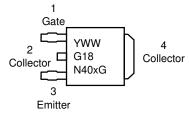
18 AMPS, 400 VOLTS  $V_{CE(on)} \le 2.0 \text{ V}$  @  $I_C = 10 \text{ A}, V_{GE} \ge 4.5 \text{ V}$ 





DPAK CASE 369C STYLE 7

## **MARKING DIAGRAM**



G18N40x = Device Code x = B or A Y = Year WW = Work Week G = Pb-Free Device

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NGD18N40CLBT4G	DPAK (Pb-Free)	2500/Tape & Reel
NGD18N40ACLBT4G	DPAK (Pb-Free)	2500/Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

## UNCLAMPED COLLECTOR-TO-EMITTER AVALANCHE CHARACTERISTICS $(-55^{\circ} \le T_J \le 175^{\circ}C)$

Characteristic	Symbol	Value	Unit
Single Pulse Collector–to–Emitter Avalanche Energy $V_{CC}=50~\text{V},~V_{GE}=5.0~\text{V},~\text{Pk}~\text{I}_{L}=21.1~\text{A},~\text{L}=1.8~\text{mH},~\text{Starting}~\text{T}_{J}=25^{\circ}\text{C}$ $V_{CC}=50~\text{V},~\text{V}_{GE}=5.0~\text{V},~\text{Pk}~\text{I}_{L}=16.2~\text{A},~\text{L}=3.0~\text{mH},~\text{Starting}~\text{T}_{J}=25^{\circ}\text{C}$ $V_{CC}=50~\text{V},~\text{V}_{GE}=5.0~\text{V},~\text{Pk}~\text{I}_{L}=18.3~\text{A},~\text{L}=1.8~\text{mH},~\text{Starting}~\text{T}_{J}=125^{\circ}\text{C}$	E <sub>AS</sub>	400 400 300	mJ
Reverse Avalanche Energy $V_{CC}$ = 100 V, $V_{GE}$ = 20 V, Pk I <sub>L</sub> = 25.8 A, L = 6.0 mH, Starting T <sub>J</sub> = 25°C	E <sub>AS(R)</sub>	2000	mJ
MAXIMUM SHORT-CIRCUIT TIMES (-55°C ≤ T <sub>J</sub> ≤ 150°C)			
Short Circuit Withstand Time 1 (See Figure 17, 3 Pulses with 10 ms Period)	t <sub>sc1</sub>	750	μs
Short Circuit Withstand Time 2 (See Figure 18, 3 Pulses with 10 ms Period)	t <sub>sc2</sub>	5.0	ms
THERMAL CHARACTERISTICS			
Thermal Resistance, Junction to Case	$R_{ heta JC}$	1.3	°C/W
Thermal Resistance, Junction to Ambient DPAK (Note 1)	$R_{\theta JA}$	95	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 5 seconds	TL	275	°C

### **ELECTRICAL CHARACTERISTICS**

Characteristic	Symbol	<b>Test Conditions</b>	Temperature	Min	Тур	Max	Unit
OFF CHARACTERISTICS			-				
Collector-Emitter Clamp Voltage	BV <sub>CES</sub>	I <sub>C</sub> = 2.0 mA	T <sub>J</sub> = -40°C to 150°C	380	395	420	$V_{DC}$
		I <sub>C</sub> = 10 mA	T <sub>J</sub> = -40°C to 150°C	390	405	430	
Zero Gate Voltage Collector Current	I <sub>CES</sub>		T <sub>J</sub> = 25°C	-	2.0	20	$\mu A_{DC}$
		$V_{CE} = 350 \text{ V}, V_{GF} = 0 \text{ V}$	T <sub>J</sub> = 150°C	-	10	40*	
	VGE - 0 V	-GE -	$T_J = -40^{\circ}C$	_	1.0	10	
		$V_{CE} = 15 \text{ V},$ $V_{GE} = 0 \text{ V}$	T <sub>J</sub> = 25°C	-	-	2.0	
Reverse Collector–Emitter Leakage Current	I <sub>ECS</sub>		T <sub>J</sub> = 25°C	-	0.7	1.0	mA
		$V_{CE} = -24 \text{ V}$	T <sub>J</sub> = 150°C	-	12	25*	
			$T_J = -40^{\circ}C$	_	0.1	1.0	
Reverse Collector-Emitter Clamp Voltage	B <sub>VCES(R)</sub>		$T_J = 25^{\circ}C$	27	33	37	$V_{DC}$
		$I_C = -75 \text{ mA}$	T <sub>J</sub> = 150°C	30	36	40	
			$T_J = -40^{\circ}C$	25	32	35	
Gate-Emitter Clamp Voltage	BV <sub>GES</sub>	$I_G = 5.0 \text{ mA}$	$T_J = -40^{\circ}\text{C}$ to 150°C	11	13	15	V <sub>DC</sub>
Gate-Emitter Leakage Current	I <sub>GES</sub>	V <sub>GE</sub> = 10 V	$T_J = -40^{\circ}\text{C} \text{ to}$ 150°C	384	640	700	μA <sub>DC</sub>
Gate Emitter Resistor	R <sub>GE</sub>	-	$T_J = -40^{\circ}\text{C}$ to 150°C	10	16	26	kΩ

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>1.</sup> When surface mounted to an FR4 board using the minimum recommended pad size. \*Maximum Value of Characteristic across Temperature Range.

## **ELECTRICAL CHARACTERISTICS (continued)**

Characteristic	Symbol	Test Conditions	Temperature	Min	Тур	Max	Unit
ON CHARACTERISTICS (Note 2)					-		
Gate Threshold Voltage	V <sub>GE(th)</sub>	T <sub>J</sub> = 25°C	1.1	1.4	1.9	$V_{DC}$	
	, ,	$I_C = 1.0 \text{ mA},$ $V_{GE} = V_{CE}$	T <sub>J</sub> = 150°C	0.75	1.0	1.4	
			$T_J = -40^{\circ}C$	1.2	1.6	2.1*	
Threshold Temperature Coefficient (Negative)	-	-	-	_	3.4	-	mV/°C
Collector-to-Emitter On-Voltage	V <sub>CE(on)</sub>		T <sub>J</sub> = 25°C	1.0	1.4	1.6	V <sub>DC</sub>
		$I_C = 6.0 \text{ A},$ $V_{GE} = 4.0 \text{ V}$	T <sub>J</sub> = 150°C	0.9	1.3	1.6	
		VGE = 4.0 V	T <sub>J</sub> = -40°C	1.1	1.45	1.7*	
			T <sub>J</sub> = 25°C	1.3	1.6	1.9*	-
		$I_{C} = 8.0 \text{ A},$ $V_{GE} = 4.0 \text{ V}$	T <sub>J</sub> = 150°C	1.2	1.55	1.8	
		VGE = 1.0 V	T <sub>J</sub> = -40°C	1.4	1.6	1.9*	
			T <sub>J</sub> = 25°C	1.4	1.8	2.05	
		I <sub>C</sub> = 10 A, V <sub>GE</sub> = 4.0 V	T <sub>J</sub> = 150°C	1.4	1.8	2.0	
		▼GE = 4.0 ▼	$T_J = -40^{\circ}C$	1.4	1.8	2.1*	
	I <sub>C</sub> = 15 A, V <sub>GE</sub> = 4.0 V		T <sub>J</sub> = 25°C	1.8	2.2	2.5	
		T <sub>J</sub> = 150°C	2.0	2.4	2.6*		
		VGE = 4.0 V	T <sub>J</sub> = -40°C	1.7	2.1	2.5	•
	I <sub>C</sub> = 10 A, V <sub>GE</sub> = 4.5 V	T <sub>J</sub> = 25°C	1.3	1.8	2.0*		
		T <sub>J</sub> = 150°C	1.3	1.75	2.0*		
		T <sub>J</sub> = -40°C	1.4	1.8	2.0*	1	
		I <sub>C</sub> = 6.5 A, V <sub>GE</sub> = 3.7 V	T <sub>J</sub> = 25°C	-	_	1.65	
Forward Transconductance	gfs	$V_{CE} = 5.0 \text{ V}, I_{C} = 6.0 \text{ A}$	T <sub>J</sub> = -40°C to 150°C	8.0	14	25	Mhos
YNAMIC CHARACTERISTICS	•			•	•	•	•
Input Capacitance	C <sub>ISS</sub>			400	800	1000	pF
Output Capacitance	C <sub>OSS</sub>	$V_{CC} = 25 \text{ V}, V_{GE} = 0 \text{ V}$ f = 1.0 MHz	$T_J = -40^{\circ}C$ to $150^{\circ}C$	50	75	100	
Transfer Capacitance	C <sub>RSS</sub>	1 = 1.0 MHZ		4.0	7.0	10	
WITCHING CHARACTERISTICS			-		-		
Turn-Off Delay Time (Resistive)	t <sub>d(off)</sub>	$V_{CC} = 300 \text{ V}, I_{C} = 6.5 \text{ A}$ $R_{G} = 1.0 \text{ k}\Omega, R_{L} = 46 \Omega,$	T <sub>J</sub> = 25°C	_	4.0	10	μSec
Fall Time (Resistive)	t <sub>f</sub>	$V_{CC} = 300 \text{ V}, I_{C} = 6.5 \text{ A}$ $R_{G} = 1.0 \text{ k}\Omega, R_{L} = 46 \Omega,$	T <sub>J</sub> = 25°C	-	9.0	15	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{CC} = 10 \text{ V}, I_{C} = 6.5 \text{ A}$ $R_{G} = 1.0 \text{ k}\Omega, R_{L} = 1.5 \Omega$	T <sub>J</sub> = 25°C	-	0.7	4.0	μSec
Rise Time	t <sub>r</sub>	$V_{CC} = 10 \text{ V}, I_{C} = 6.5 \text{ A}$ $R_{G} = 1.0 \text{ k}\Omega, R_{L} = 1.5 \Omega$	T <sub>J</sub> = 25°C	-	4.5	7.0	

<sup>2.</sup> Pulse Test: Pulse Width  $\leq 300~\mu\text{S}$ , Duty Cycle  $\leq 2\%$ . \*Maximum Value of Characteristic across Temperature Range.

### TYPICAL ELECTRICAL CHARACTERISTICS (unless otherwise noted)

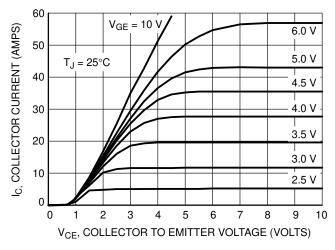


Figure 1. Output Characteristics

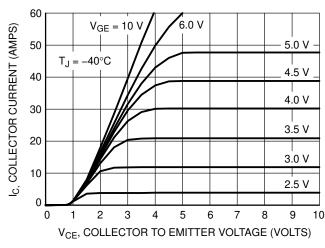


Figure 2. Output Characteristics

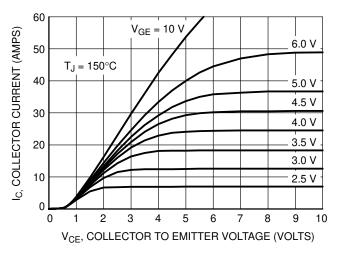


Figure 3. Output Characteristics

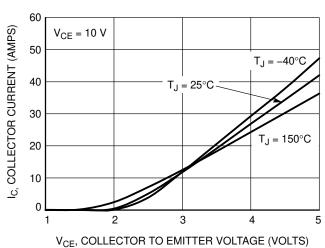


Figure 4. Transfer Characteristics

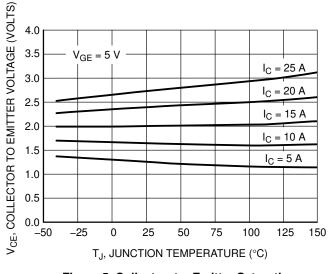


Figure 5. Collector-to-Emitter Saturation Voltage versus Junction Temperature

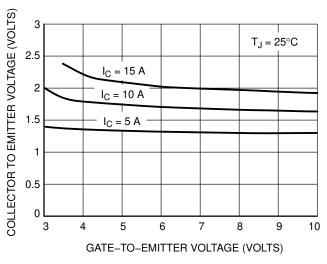
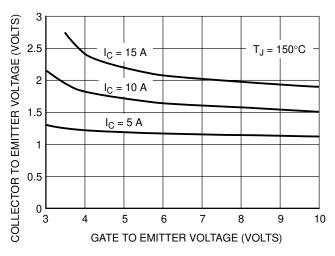


Figure 6. Collector-to-Emitter Voltage versus Gate-to-Emitter Voltage

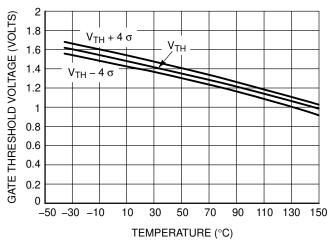
## TYPICAL ELECTRICAL CHARACTERISTICS (unless otherwise noted)



10000 1000 Ciss 1000 Coss 1000 Crss 1000 1000 Crss 1000

Figure 7. Collector-to-Emitter Voltage versus Gate-to-Emitter Voltage

Figure 8. Capacitance Variation



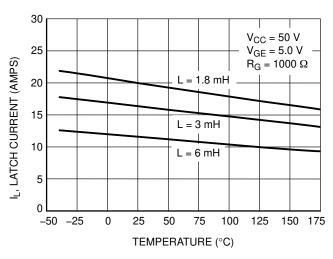
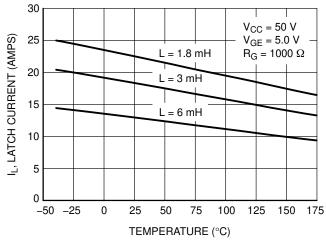


Figure 9. Gate Threshold Voltage versus Temperature

Figure 10. Minimum Open Secondary Latch Current versus Temperature



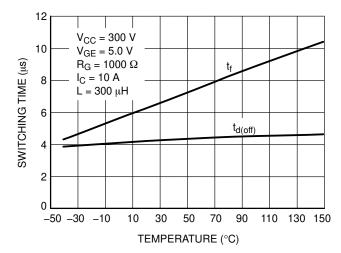


Figure 11. Typical Open Secondary Latch Current versus Temperature

Figure 12. Inductive Switching Fall Time versus Temperature

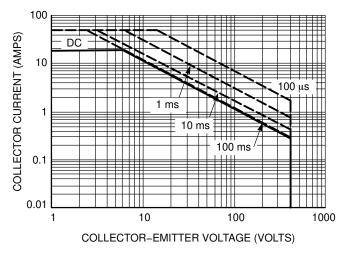


Figure 13. Single Pulse Safe Operating Area (Mounted on an Infinite Heatsink at  $T_A = 25$ °C)

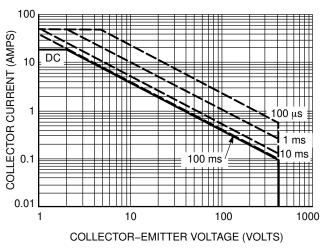


Figure 14. Single Pulse Safe Operating Area (Mounted on an Infinite Heatsink at  $T_A = 125$ °C)

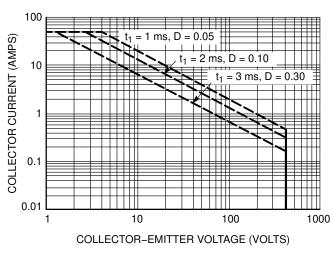


Figure 15. Pulse Train Safe Operating Area (Mounted on an Infinite Heatsink at  $T_C = 25$ °C)

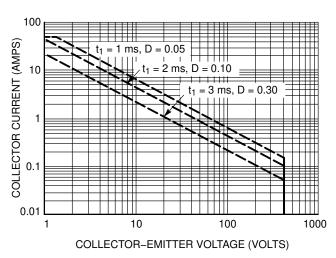


Figure 16. Pulse Train Safe Operating Area (Mounted on an Infinite Heatsink at  $T_C = 125$ °C)

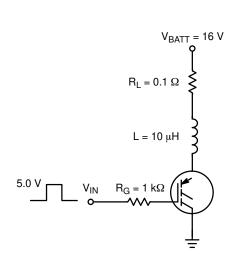


Figure 17. Circuit Configuration for Short Circuit Test #1

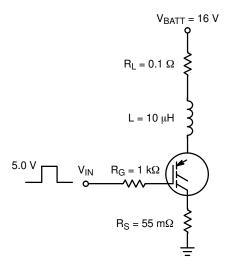


Figure 18. Circuit Configuration for Short Circuit Test #2

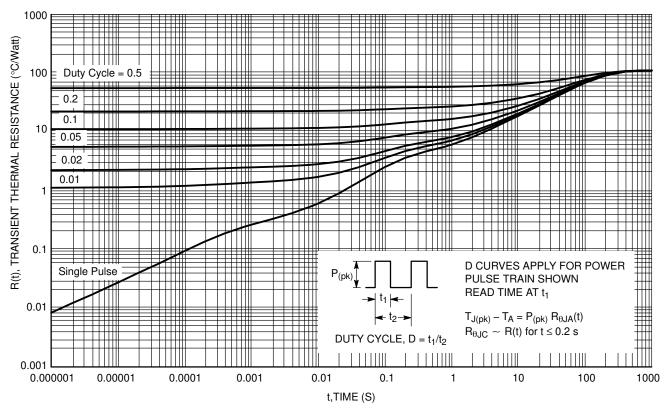
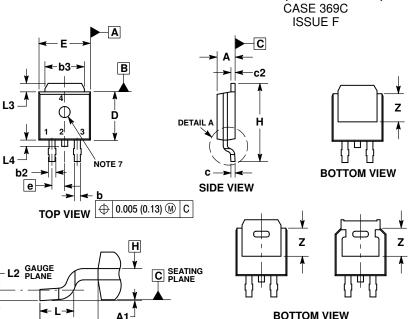


Figure 19. Transient Thermal Resistance (Non-normalized Junction-to-Ambient mounted on minimum pad area)

#### PACKAGE DIMENSIONS

## **DPAK (SINGLE GAUGE)**



#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME
- Y14.5M, 1994.
  2. CONTROLLING DIMENSION: INCHES.
  3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-
- MENSIONS b3, L3 and Z.

  4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
- 5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DATUMS A AND B ARE DETERMINED AT DATUM
- 7. OPTIONAL MOLD FEATURE.

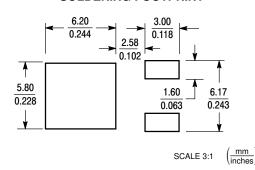
	INC	HES	MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.028	0.045	0.72	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
Е	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29 BSC		
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.114	REF	2.90 REF		
L2	0.020	BSC	0.51 BSC		
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

#### STYLE 7:

- PIN 1. GATE 2. COLLECTOR
  - EMITTER COLLECTOR

### **SOLDERING FOOTPRINT\***

AI TERNATE



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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**DETAIL A** 

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